


Search Notes 	Application/Control No. 10598934	Applicant(s)/Patent Under Reexamination NAKAHATA ET AL.
	Examiner SELIM AHMED	Art Unit 2826

SEARCHED			
Class	Subclass	Date	Examiner
257	13, 103, E33.033, E33.023	12/13/08	/sa/
438	46, 483, 481	12/13/08	/sa/
	Updated search	5/28/2009	/sa/
	Updated search	1/14/2010	/sa/

SEARCH NOTES		
Search Notes	Date	Examiner
Text search such as, Group III, III-V, nitride, GaN, GaInN, GaAlN, InGaN, AlGaIn, separate/sever/cleave/lasing/etching, substrate, crystal, nuclei/nucleus, seed, orientation, face, orientation, angle, degree, and their boolean combinations were searched.	12/13/08	/sa/
Updated search	5/28/2009	/sa/
Inventor search	1/14/2010	/sa/
Updated search	1/14/2010	/sa/
Primary Examiner Thomas Dickey was consulted for this application.	1/12/2010	/sa/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
438	481, 483	1/14/2010	/sa/
257	13, 103, E33.023	1/14/2010	/sa/

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